Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/750,466	LEE ET AL.
Examiner	Art Unit
Nyeemah Grazier	1626

SEARCHED				
Class	Subclass	Date	Examiner	
544	153, 170	6/30/2005	NG	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH N (INCLUDING SEARC	IOTES CH STRATEGY	
	DATE	EXMR
Classification	6/30/2005	NG
STN (Structure + Process)	6/29/2005	NG
Inventor Name	6/30/2005	NG